

<b>Notice of References Cited</b>	Application/Control No. 10/644,603	Applicant(s)/Patent Under Reexamination YAMADA ET AL.	
	Examiner Alexander O. Williams	Art Unit 2826	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	NA84035027 "Low Inductance Chip Tester Interposers" IBM Technical Disclosure Bulletin, March 1984, US Vol # 26, Issue # 10A, page # 5027-5030; Publication date 3/1/84
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